

Phase II prototype detectors (Segmented, n-type)

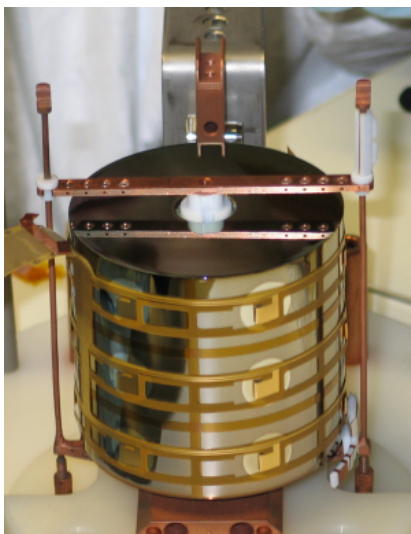


Outline



- Gerdalinchen II teststand filled with LN:
 - Latest run with SiegfriedII
 - validation of the PS simulation
- Vacuum cryostat:
 - SiegfriedII running in vacuum
 - Scan with collimated Eu152
 - Th228 data
- Gerdalinchen II teststand filled with LAr
 - Siegfried I in LAr
 - Long term leakage current measurement
 - Capacity measurements

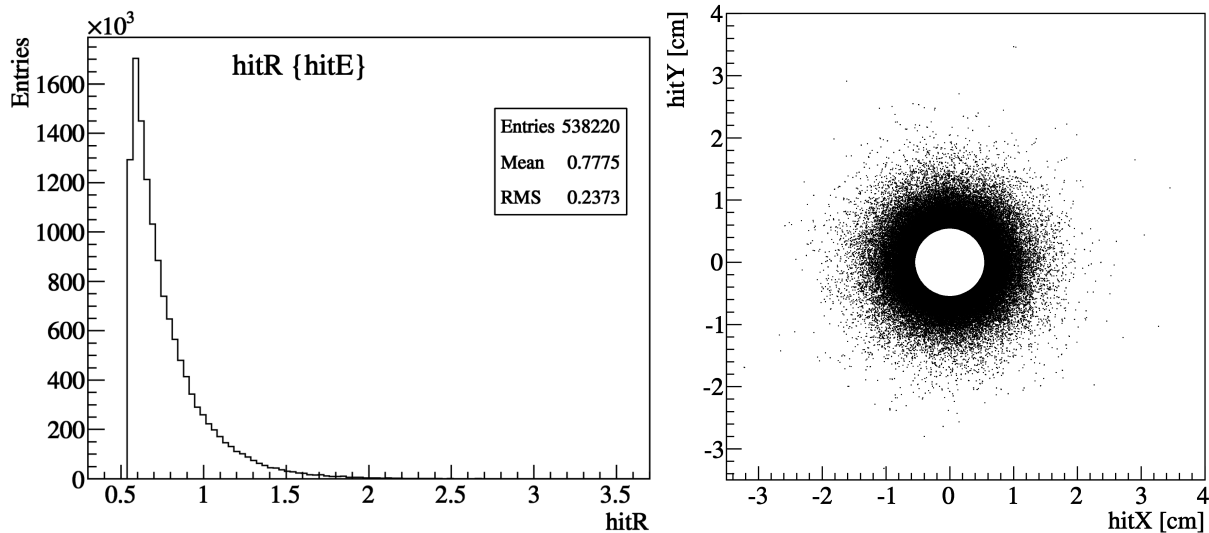
SiegfriedII in LN



- SiegfriedII was running in LN from 24.03.09 to 29.04.09
- Cadmium-109 source was placed inside the borehole in the crystal
- The 88keV line seen only in the "top" segments
- Pulse shapes were recorded to validate PS simulation



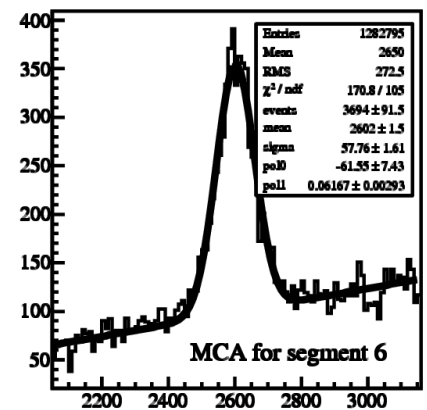
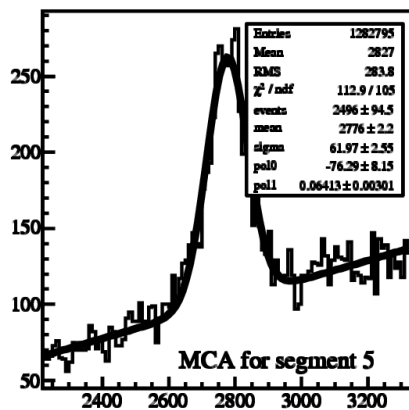
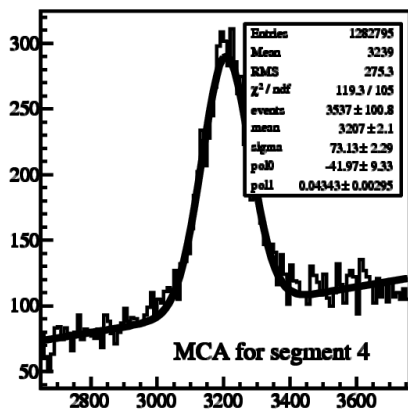
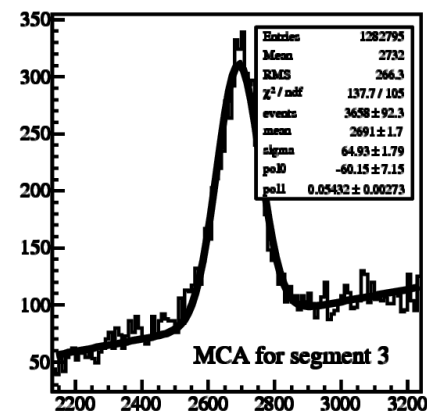
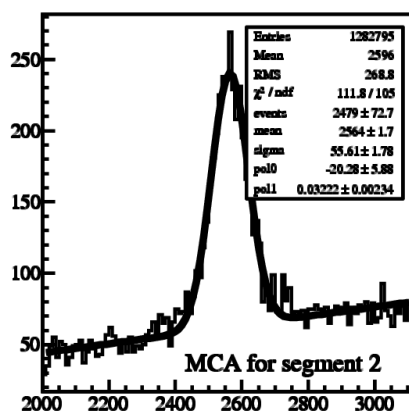
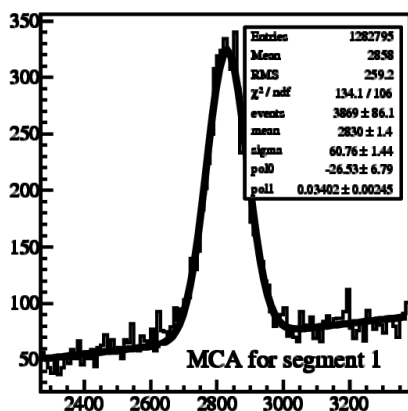
Cd109 - Simulation



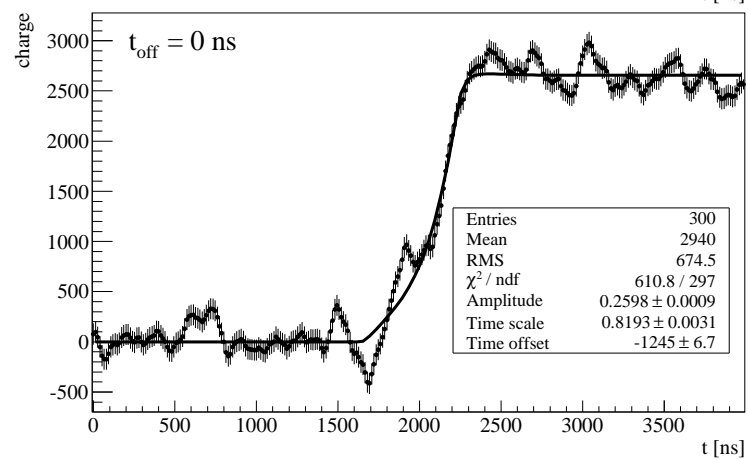
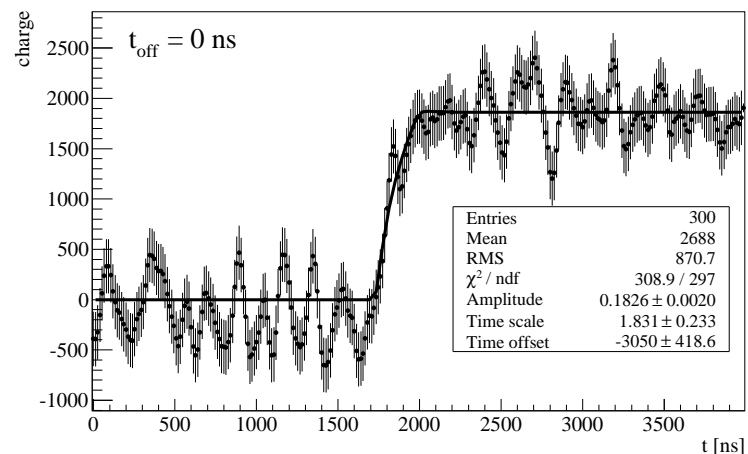
Hits are distributed close to the core, the pulse-shapes are mainly defined by the hole drift



88keV line

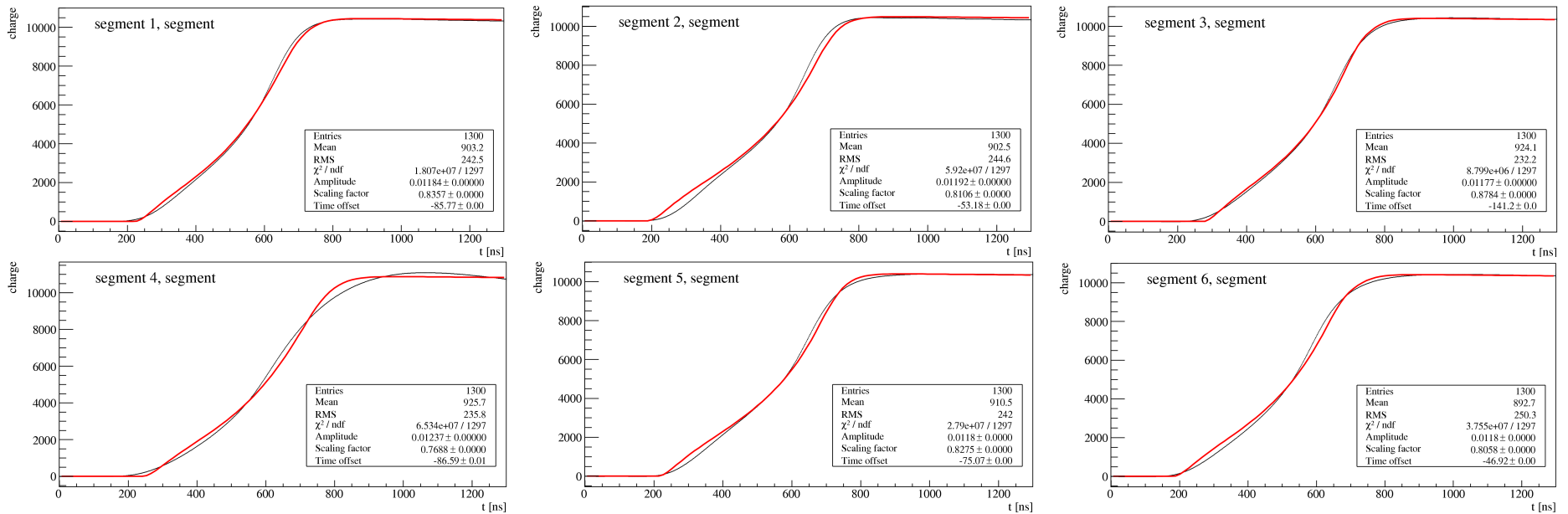


Real pulses + simulation



To reduce the noise average pulses were used

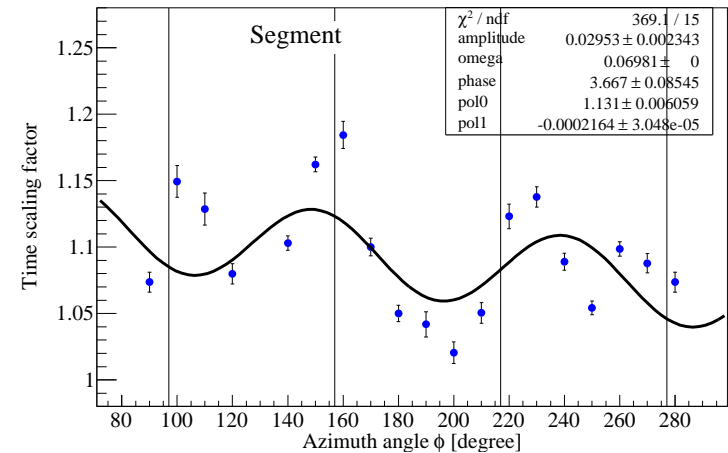
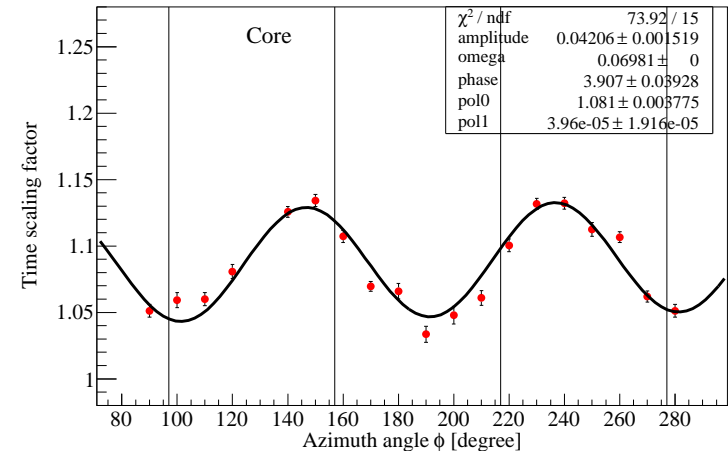
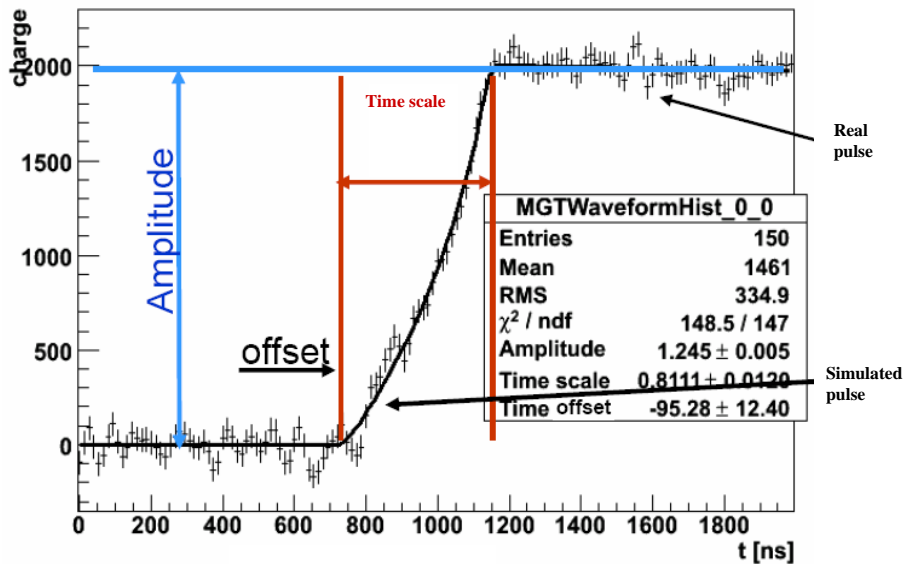
Average pulses (black) for all the top 6 segments with the simulated pulses (red)



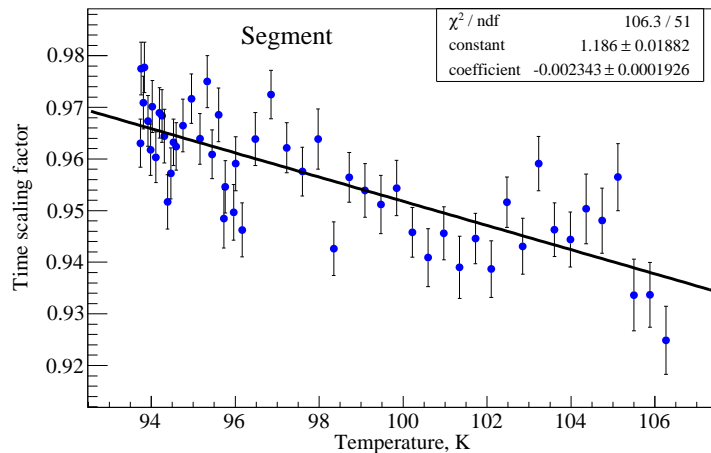
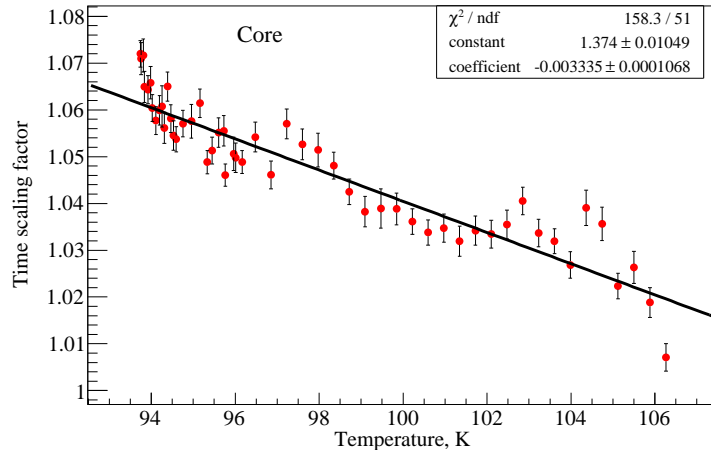
good agreement with the simulation



The simulated pulse is scaled vertically and horizontally to fit the real pulse. Horizontal stretching = "time scaling"

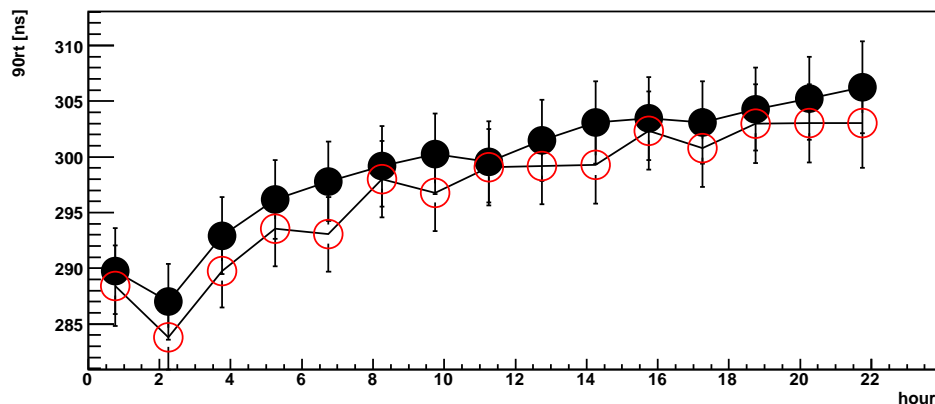


- Angular scan with collimated Eu152 source
- Crystal axes clearly visible

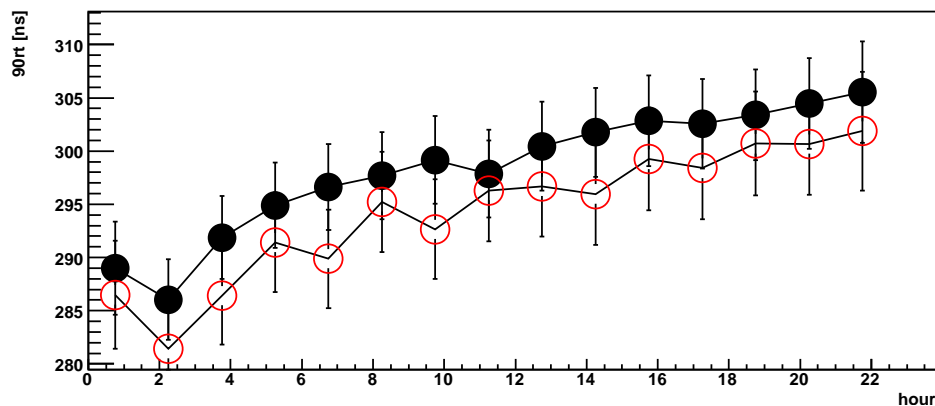


- Temperature continuously increases between refills
- Rise time changes with time
→ Temperature dependent
- Consequences on the PS analysis

Graph



Graph



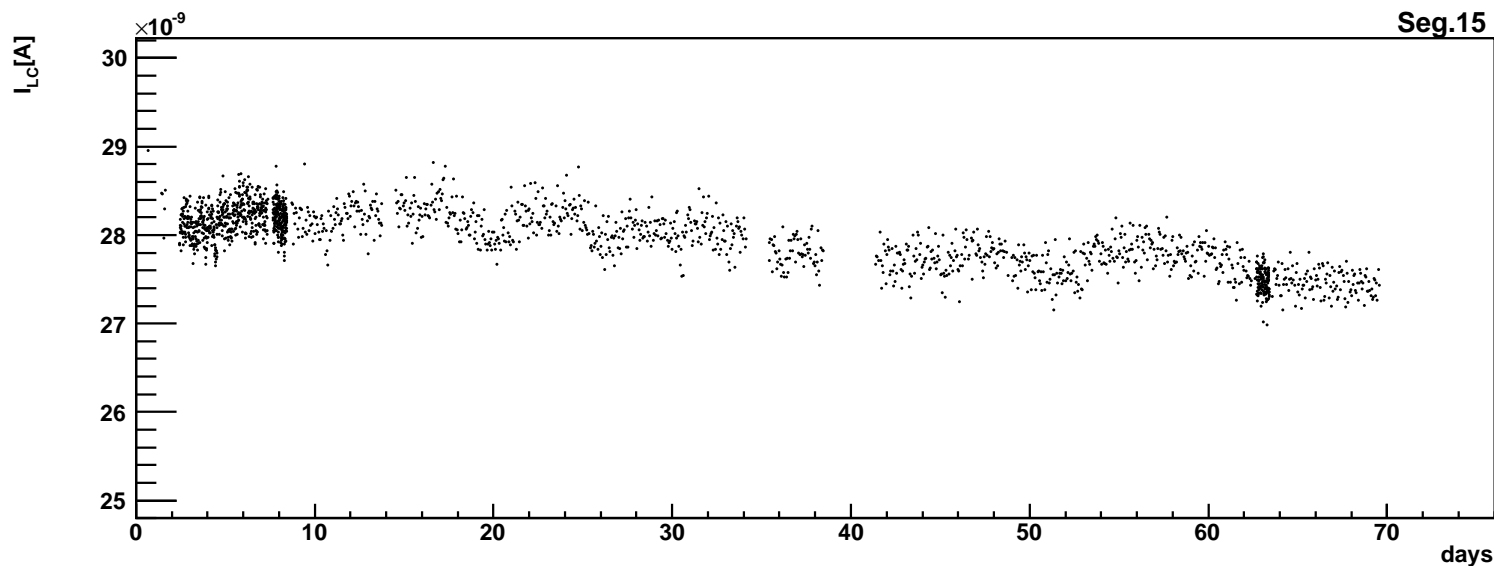
- Th228 data
- black dots: DEP peak
- open dots: 1620keV peak
- upper plot all events
- lower plot single-segment events.



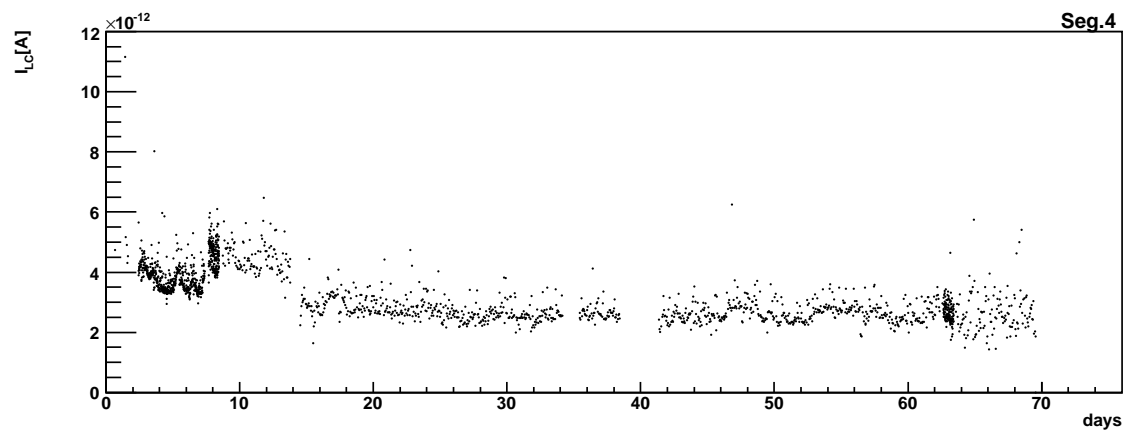
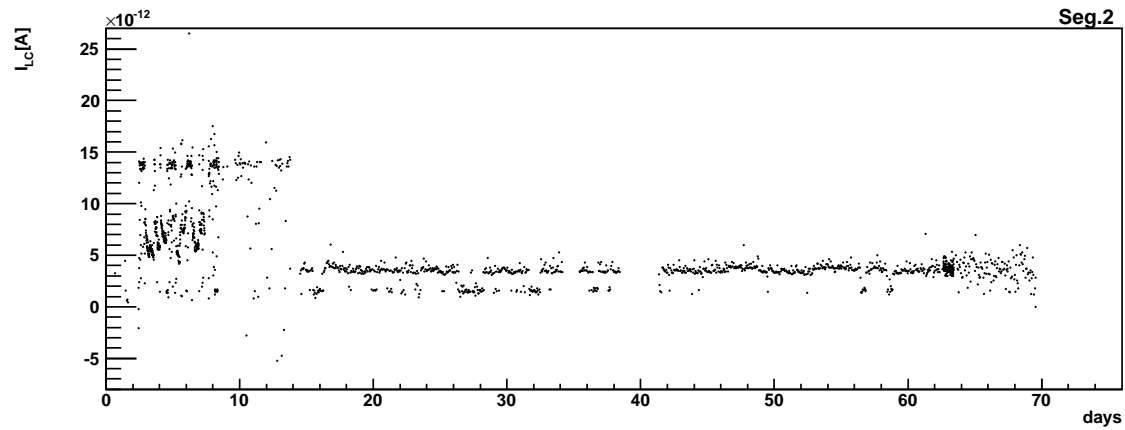
Siegfried I in LAr



Siegfried I in LAr since (almost) 4 month (started on 29.05.09)
Automatic measurement: LabView + Keithley pico amp. meter
Leakage current measured every hour for all 18 segments.
One broken segment $I_{LC} = 28nA$



Stable for more than 3 month, examples:





Capacity measurements



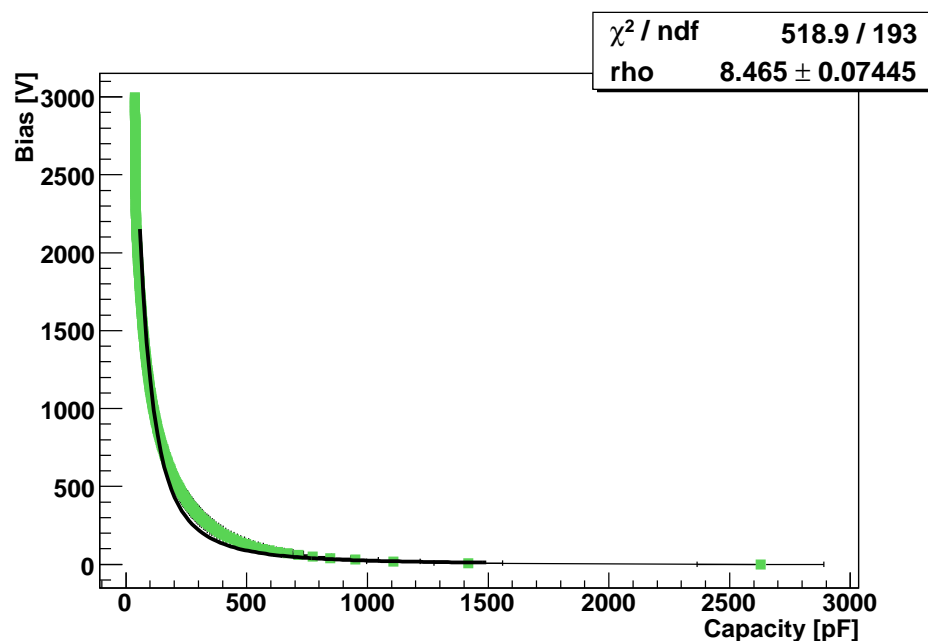
- We measured the capacities of SI as a function of bias voltage, core and all the segments one by one
- The C(V) curve can be fitted with:

$$V_d = \frac{\rho}{2\epsilon} \left[r_1^2 \ln \left(\frac{r_2}{r_1} \right) - \frac{1}{2}(r_2^2 - r_1^2) \right] \quad (1)$$

- Impurity concentration can be determined
- From the resistance, resistivity and mobility can be calculated

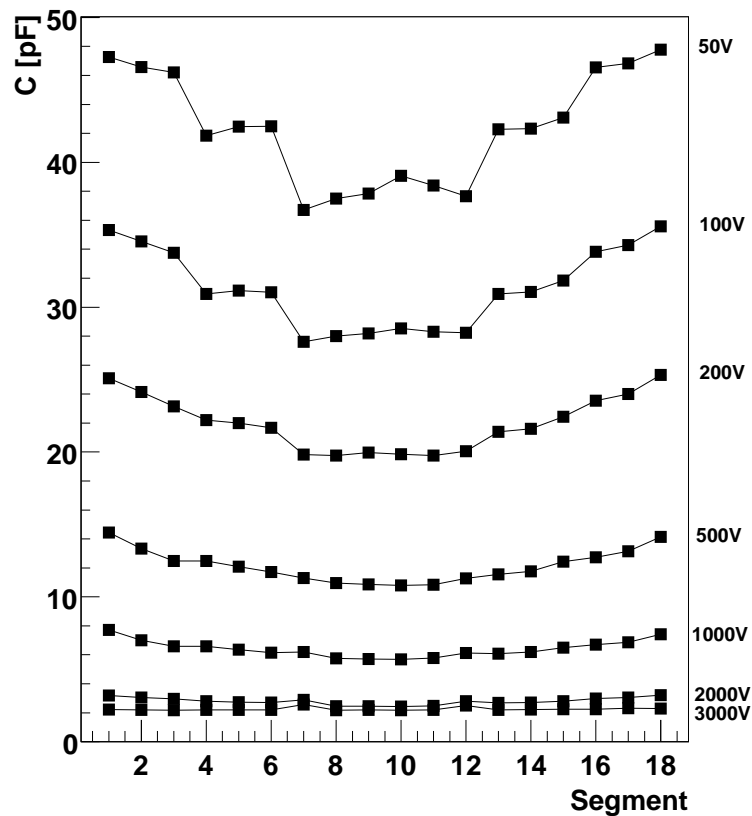


Core capacity



Bias voltage v. core capacity fitted with the formula. From the fit the donor concentration is $8.5 \times 10^9 / \text{cm}^3$ Good agreement with the values given by Canberra

Segment capacities



From the segment capacities (as function of bias voltage) the vertical gradient can be reconstructed



Impurity concentrations



	Resistance k Ω	Resistivity Ω cm	Capacity pF	Impurity conc. 10^9 /cm ³	Mobility m ² /VS
Core	1.021	24494.6	37.76	8.23	3.09
Top	2.675	21394.0	12.64	9.08	3.21
Middle	3.094	24742.4	12.44	8.14	3.09
Bottom	3.525	28193.5	13.01	7.61	2.90
Seg.1	15.76	21010.2	2.23	9.94	2.98
Seg.2	15.97	21290.3	2.20	9.24	3.17
Seg.3	16.36	21809.1	2.17	8.79	3.25
Seg.4	18.40	24529.7	2.20	8.72	2.91
Seg.5	18.37	24492.7	2.18	8.42	3.02
Seg.6	18.63	24840.4	2.20	8.24	3.04
Seg.7	21.34	28448.3	2.57	8.15	2.69
Seg.8	21.32	28425.1	2.17	7.63	2.87
Seg.9	20.88	27835.3	2.18	7.57	2.96
Seg.10	21.03	28031.5	2.18	7.52	2.96
Seg.11	21.00	27986.3	2.20	7.64	2.91
Seg.12	20.92	27889.0	2.49	8.06	2.77
Seg.13	18.53	24700.7	2.20	8.13	3.10
Seg.14	18.63	24831.3	2.21	8.27	3.03
Seg.15	18.04	24054.1	2.24	8.66	2.99
Seg.16	16.16	21546.7	2.25	8.92	3.24
Seg.17	15.95	21263.0	2.30	9.11	3.22
Seg.18	15.45	20596.1	2.28	9.76	3.10



Summary



- PS simulation was validated with real data also for segment pulses dominated by the hole drift.
- Temperature dependence of the rise time observed in vacuum cryostat
- We don't see an increase of the leakage current in LAr after more than 3 month continuous measurement
- Impurity concentration and its spatial distribution was estimated from capacity measurement for SI.